

Please amend the application as follows:

**In the Specification:**

*On page 5, in the paragraph beginning at line 10, please delete the paragraph and insert the following:*

--Advantages of the disclosed methods and structures, in various embodiments, can include one or more of the following:

- more test structures can be made larger;
- quicker correction of process deviations;
- increased efficiency of use of wafer area;
- increased efficiency of use of scribeline area;
- fewer probe pads are needed;
- increased yield;
- increased capability for "early warning" testing increases reliability of the integrated circuits.--

**In the Abstract:**

*Please delete the Abstract and insert the following:*